

Attorney Docket No.: 0180212

Please enter the following amended Abstract:

A system and method for testing a flash memory device having uniform sectors and smaller, "boot" sectors includes determining uniform and boot test limits. The uniform and boot test limits are determined based on average erase and APDE time periods of the uniform and boot sectors, respectively. In this way, the erase test results for each sector type is compared against test limits that are based only on that sector type, thereby avoiding excessive false rejects.